

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Andrecev, *et al.*
Serial No.: 10/646,535
Filed: August 22, 2003
Title: SYSTEM AND METHOD FOR EFFICIENTLY TESTING A LARGE
RANDOM ACCESS MEMORY SPACE
Grp./A.U.: 2138
Confirmation No. 9860
Examiner: Dipakkumar B. Gandhi

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this correspondence is being electronically filed with United States Patent and trademark Office on:	
April 27, 2006	(Date)
Margaret A. Jess	
(Printed or typed name of person signing the certificate)	
Margaret A. Jess	
(Signature of the person signing the certificate)	

Sir:

AMENDMENT UNDER 37 C.F.R. § 1.111

In response to the Examiner's Action mailed February 10, 2006, please amend the above-identified application as follows:

IN THE SPECIFICATION:

[0031] As stated above, the combinatorial logic 180 employs the portion stored in the pseudo-memory 170 and corresponding data-out bit patterns read from the plurality of RAM arrays 160 to generate a response bit pattern that matches the probe bit pattern only if all of the data-out bit patterns match the probe bit pattern.

[0031] As stated above, the combinatorial logic 180 employs the portion stored in the pseudo-memory 170 and corresponding data-out bit patterns read from the plurality of RAM arrays 120 to generate a response bit pattern that matches the probe bit pattern only if all of the data-out bit patterns match the probe bit pattern.